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| <b>Issue Classification</b><br> | <b>Application/Control No.</b> | <b>Applicant(s)/Patent Under Reexamination</b> |
|  | 10619801                       | KIM, BENJAMIN JUNG                             |
| <b>Examiner</b>  | <b>Art Unit</b>                |  |
|  | Faulk, Devona E                | 2615   |

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|---|---------------------|--|----------------------------|--------------------------|-------------------------|
| Faulk, Devona E<br>(Assistant Examiner) | 9/13/2007<br>(Date) | VIVIAN CHIN<br>SUPERVISORY PATENT EXAMINER<br>TECHNOLOGY CENTER 2930<br><i>[Signature]</i> | Total Claims Allowed:<br>9 |                          |                         |
| (Legal Instruments<br>Examiner)         | (Date)              | (Primary Examiner)   | (Date)                     | O.G. Print Claim(s)<br>1 | O.G. Print Figure<br>26 |